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APPLICANT Paul Hansma, et al.

RECEIVED  
AUG 12 1997  
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LIST OF PATENTS AND PUBLICATIONS FOR  
APPLICANT'S INFORMATION DISCLOSURE  
STATEMENT

(USE SEVERAL SHEETS IF NECESSARY)

FILING DATE  
9/6/96

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS IF APPROPRIATE	FILING DATE
	AA 4,935,634	6-19-90	Hansma et al			
	AB 5,164,791	11-17-92	Kubo et al.			
	AC 5,172,002	12-15-92	Marshall			
	AD 5,206,702	4-27-93	Kato et al.			
	AE 5,231,286	7-27-93	Kajimura et al.			
	AF 5,260,824	11-9-93	Okada et al.			
	AG 5,291,775	3-4-92	Gamble et al.			
	AH 5,298,975	3-29-94	Khoury et al.			
	AI 5,388,452	2-14-95	Harp et al.			
	AJ 5,394,741	3-7-95	Kajimura et al.			
	AK 5,406,833	4-18-95	Yamamoto			

FOREIGN PATENT DOCUMENTS

TRANSLATION	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
AL							

OTHER ART (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

AM	Drake et al.: "Imaging crystals, polymers and processes in water with the atomic force microscope," <u>Science</u> , Vol. 243, 1586 (1989) <i>(no month)</i>
AN	Hansma et al.: "A new, common optical-lever based atomic force microscope," <u>J.Appl.Phys.</u> , Vol. 76, 796 (1994) <i>(no month)</i>
AO	Clark et al.: "A high performance scanning force microscope head design," <u>Rev.Sci.Instrum.</u> , Vol. 64, No. 4, 904 (1993) <i>(no month)</i>
AP	Baselt, et al.: "Scanned-cantilever atomic force microscope head design," <u>Rev. Sci.Instrum.</u> , Vol 64, No. 4, 908 (1993) <i>(no month)</i>
AQ	Walters, et al.: "Short cantilevers for atomic force microscopy," <i>(no date)</i>

✓ AR Hipp et al.: "A stand-alone scanning force and friction microscope," Ultramicroscopy, Vol 42-44, 1498-1503 (1992). (no month)

✓ AS Alexander, et al.: "An atomic resolution atomic-force microscope implemented using an optical lever" J. Appl. Phys., Vol. 65, 164-167 (1989) (no month)

✓ AT Binnig et al.: "Atomic Force Microscope" Phy.Rev.Let., Vol. 56, No. 9 (1986) (no month)

✓ AU Chalmers et al: "Determination of tilted superlattice structure by atomic force microscopy" Appl. Phys. Let., Vol. 55, No. 24 (1989) (no month)

✓ AV Dietz et al.: "Atomic Force Microscopy of C<sub>60</sub>/C<sub>70</sub> Single-Crystal Fullerenes under Ethanol" Applied Phys., A.56, 207-210 (1993) (no month)

✓ AW Dietz et al.: "Molecular structure and thickness of highly oriented poly (tetrafluoroethylene) films measured by atomic force microscopy" J. of Materials Sci., (1993). (no month)

✓ AX Erlandsson et al.: "Atomic force micrsopy using optical interferometry" J. Vac.Sci.Technol.(1988) (no month)

✓ AY Hansma et al.: "Scanning Tunneling Microscopy and Atomic Force Microscopy: Application to Biology and Technology" Science, Vol. 242, pgs. 209-242 (1988) (no month)

✓ AZ Hansma et al: "A new optical lever based atomic force microscope" J. Appl. Phys., Vol. 76, (1994) (no month)

✓ BA Hillner et al.: "AFM images of dissolution and growth on a calcite crystal" Ultramicroscopy, pgs. 1387-1393 (1992) (no month)

✓ BB Hillner et al.: "Combined Atomic Force and Scanning Reflection Interference Contrast Microscopy; Scannning, Vol. 17, 144-147 (1995) (no month)

✓ BC Hillner et al.: "Combined Atomic Force and Confocal Laser Scanning Microscope" JMSA, Vol. 1, No. 3, 127-130 (1995) (no month)

✓ BD Kees, et al.: "Compact stand-alone atomic force microscope," Rev. Sci.Instrum., Vol 64, No. 10, (1993) (no month)

✓ BE Jung, et al.: "Novel stationary sample atomic force microscope with beam tracking lens" (no date)

✓ BF Marti et al.: "Atomic force microscopy of liquid covered surfaces: atomic resolution images," Appl.Phys.Let., Vol 51, No. 7 (1987). (no month)

✓ BG Marti, et al.: "A atomic force micrsopy of an organic monolayer" Science, Vol. 239(1988) (no month)

BH Marti et al.: "Atomic resolution force microscopy of graphite and the 'native oxide' on silicon" Dept. of Physics, UCSB, (1987) (no month)

BI Marti et al: "Atomic force microscopy and scanning tunneling microscopy with a combination atomic force microscope/scanning tunneling microscope" J.Vac.Sci.Techol., A6(3)(1988) (no month)

BJ Marti et al.: "Control electronics for atomic force microscopy" Rev.Sci.Instrum, (1988) (no month)

BK Marti et al.: "Probing surfaces with the atomic force microscope" SPIE, Vol. 897 (1988). (no month)

BL Meyer et al.: "Erratum: Novel optical approach to atomic force microscopy" Appl. Phys. Let. Vol. 53 (1988) (no month)

BM Putman et al.: "A theoretical comparison between interferometric and optical beam deflection technique for the measurement of cantilever displacement in AFM" Ultramicroscopy, pp. 1509-1513 (1992) (no month)

BO Putman et al: "Polymerized LB films imaged with a combined atomic force microscope-fluorescent microscope" Langmuir, Vol. 8, pp. 3014-3019 (1992) (no month)

BP Putman et al.: "Immunogold labels: cell-surface markers in atomic force microscopy," Ultramicroscopy, Vol 48, pp. 177-182 (1993). (no month)

BQ Radmacher et al.: "An AFM with integrated micro fluorescence optics: design and performance" Ultramicroscopy, pp. 968-972 (1992) (no month)

BR Ruger et al.: "Atomic force microscopy" Physics Today, (1990) (no month)

BS Walters et al: "Atomic force microscope integrated with a scanning electron microscope for tip fabrication" App. Phys. Let., Vol. 65 (1994) (no month)

BT Radmacher et al.: "Scanning nearfield optical microscope using microfabricated probes" Rev.Sci.Instrum, Vol. 65 2737 (1998) (no month)

BU Martin et al.: "Atomic force microscope mapping and probing on a sub-100-A scale" J.App.Phys. (no date)

BV Walters et al. "Cantilevers for atomic force microscopy" UCSB, Dept. of Physics (no date)

EXAMINER

John R. Lee

DATE CONSIDERED

10-25-97

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.